


<b>Search Notes</b> 	<b>Application/Control No.</b> 10538126	<b>Applicant(s)/Patent Under Reexamination</b> KUROIWA ET AL.
	<b>Examiner</b> Jaisle, Cecilia M	<b>Art Unit</b> 1624

SEARCHED			
Class	Subclass	Date	Examiner
514	248	9/21/2007	Cecilia Jaisle
540	461, 578	9/21/2007	Cecilia Jaisle
544	235, 236	9/21/2007	Cecilia Jaisle
514	248	5/7/2008	C. Jaisle
544	235, 236	8/21/2008	C. Jaisle

SEARCH NOTES		
Search Notes	Date	Examiner
STN and Inventor Names searched by STIC	9/21/2007	Cecilia Jaisle

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
544	235, 236	8/21/2008	C. Jaisle